ELE 404: Electronics I Lab 1: Diodes

### Introduction

In this lab you will examine the v-i characteristic of the 1N4148 silicon diode. You will also study the small-signal behavior of the diode in the forward-bias region.

## **Pre-lab Assignment**

**P1.**Simulate the circuit of **Figure 1**, assuming that the diode is the **1N4148** and  $R = 1 k\Omega$ . Also assume that  $v_s$  is a 1-kHz symmetrical triangular voltage whose peak-to-peak swing is 24 volts. Further, assume the source resistance  $R_S$  to be 50  $\Omega$ . Present the waveforms of  $v_S$ ,  $v_I$ ,  $i_D$ , and  $v_D$ , for three cycles (periods) as **Graph P1(a)**. Also, present a plot of  $i_D$  versus  $v_D$ , as **Graph P1(b)**.

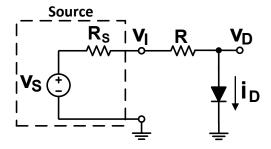
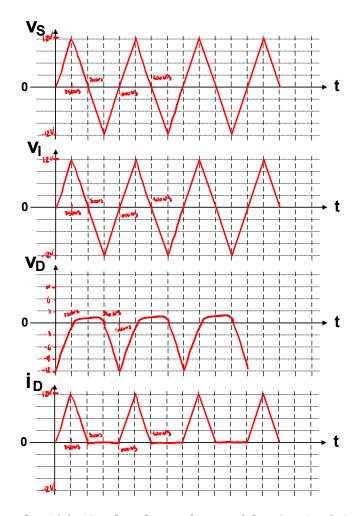
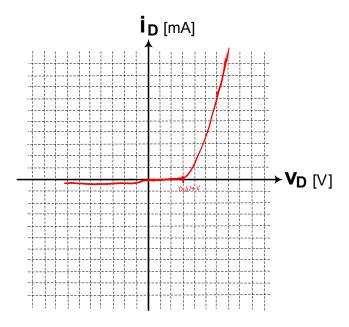


Figure 1. A voltage source driving a diode through a series resistance.



Graph P1(a). Simulated waveforms of the circuit of Figure 1.



Graph P1(b). Voltage-current characteristic of the diode.

#### **Experiment and Results**

**E1.** The main objective of this experiment is to understand the small-signal behavior of a diode, and to calculate its small-signal (AC) resistance at different quiescent current values. To that end, construct the circuit of **Figure 2(a)** with a 1N4148 as the diode, and a 1- $k\Omega$  resistor as resistor R. Set the multimeter to the DC voltage measurement mode and have it handy. Then, turn on the power supply and raise  $V_{CC}$  in such a way that the voltage across the resistor,  $v_R$  (that indeed is  $V_{CC} - v_D$ ) becomes equal to 10 volts; this corresponds to a diode current of about  $i_D = 10 \ mA$  (assume that R is precisely 1  $k\Omega$ ). Record the diode voltage as  $v_{D1}$ . Also, record the corresponding value of  $V_{CC}$ . Next, connect a 1.5- $k\Omega$  resistor,  $R_{Sh}$ , across the diode as **Figure 2(b)** illustrates, and record the diode voltage as  $v_{D2}$ . The function of the *shunt* resistance  $R_{Sh}$  is to change the diode current by the small amount  $\Delta i_D = -v_{D2}/R_{Sh}$  (the negative sign shows that  $i_D$  becomes smaller after the connection of  $R_{Sh}$ ), amounting to about 5% to 7% of the initial value of  $i_D$ . Complete the first row of **Table E1** with the recorded values. Then, repeat the test for the other values of  $v_R$  and  $R_{Sh}$  as listed in **Table E1**.

**Tip:** After setting  $v_R$ , connect your multimeter probes across the diode and hold them there waiting for the reading to stabilize. Record the stable voltage as  $v_{D1}$ . Then, while still holding the probes, connect the resistor  $R_{sh}$  and quickly record the new voltage as  $v_{D2}$ . Record  $v_{D1}$  and  $v_{D2}$  with the maximum number of digits displayed by the multimeter.

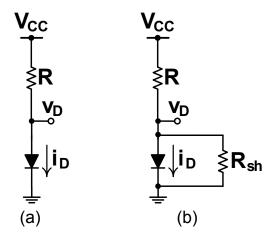


Figure 2. (a) A diode biased with a DC power supply and (b) the same circuit but with a shunt resistor connected across the diode.

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**Table E1.** Test results for the circuits of **Figure 2(a)** and **Figure 2(b)**.

$i_{D1}[mA]$	$V_{cc}[V]$	$v_{D1}[V]$	$R_{sh}\left[k\Omega\right]$	$v_{D2}[V]$	$\Delta v_D [V] = v_{D2} - v_{D1}$	$\Delta i_D [mA] = -\frac{v_{D2}}{R_{sh}}$	$= \frac{r_d [\Omega]}{\Delta i_D} \times 1000$
10	10.79	0.7332	1.5	0.7270	006Z	-0,4846	12,74
7	7.76	0.7142	2.2	0.7079	-0.0063	- 0,3217	14.58
5	5.71	0.6969	2.7	0.6877	- 0.00 4z	- () , 2547	36.12
2	2.66	0.6521	6.8	0.6444	- 0.00 77	-0.094%	81.25
1	1.60	0.6186	12	0.6096	-0.009	- O. OSOB	177,16

#### **Conclusions and Remarks**

- **C1.** Describe the waveforms of **Graph P1(a)**, and explain what is happening. Also, comment on the *v-i* characteristic of **Graph P1(b)**. Did you expect this characteristic curve? Explain.
- **C2.** As discussed in the lectures, the diode characteristic in the forward region is described by

$$i_D = I_S \left( e^{\left(\frac{v_D}{nV_T}\right)} - 1 \right)$$

where  $I_S$  is the *saturation current*,  $V_T$  is the *thermal voltage* (approximately 25 mV at room temperature), and n is an *ideality factor* whose value is between 1 and 2, depending on the material, structure, etc., of the diode. In our course, we often assume n to be unity, for the sake of simplicity. However, as the following exercise shows, this is not necessarily the case.

Using the data of **Table E1**, for example those corresponding to 10 mA and 1 mA (i.e., the two current extremes in your test), **calculate**  $I_S$  **and** n **for your diode**. Then, **write a program code (e.g., in Matlab) and plot the** v-i **characteristic of your diode** for the voltage range  $0 \le v_D \le 1.1 \ V$ . If, however, the diode current corresponding to  $v_D = 1.1 \ V$  turns out to be larger than 20 mA, limit the vertical axis range of the plot to 20 mA (hence; also limit the horizontal axis range to the value of  $v_D$  that corresponds to  $i_D = 20 \ mA$ ). Present the curve as **Graph C2**.

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**C3.** As also discussed in the lectures, the small-signal resistance of a forward-biased diode is theoretically given by  $r_d = nV_T/I_D$ , where  $I_D$  is the quiescent current (or the operating-point current) of the diode. Thus,  $r_d$  will be in ohms if  $V_T$  and  $I_D$  are expressed in mV and mA, respectively.

Using the ideality factor that you calculated in **Part C2**, compare the theoretical values of  $r_d$  (based on  $r_d = nV_T/I_D$ ) and the measured values of  $r_d$  (listed in **Table E1**) for each of the quiescent currents listed in **Table E1** (10 mA, 7 mA, ...), and complete **Table C2**. Calculate the percent error from the following expression:

$$e\% = \frac{theoretical\ value - measured\ value}{measured\ value} \times 100$$

**Table C2.** Theoretical and measured values of the small-signal resistance of the diode.

Quiescent Current, $I_D$ [ $mA$ ]	10	7	5	2	1
Theoretical value of $r_d$ (from $r_d = nV_T/I_D$ )					
Measured value of $r_d$ (Table E1)					
Percent error, e%					

**C4.** Do the results of **Table E1** agree with the common understanding that the diode voltage rises by about **60***n* **mV** for an increase in current of one decade (support your answer by numbers)? If not, what could be the reason(s)?

# **TA Copy of Results**

Table E1. Test results for the circuits of Figure 2(a) and Figure 2(b).

$i_{D1}[mA]$			$R_{sh}\left[k\Omega\right]$		$\Delta v_D [V]$ $= v_{D2} - v_{D1}$	$\Delta i_D [mA] = -\frac{v_{D2}}{R_{sh}}$	$r_d \left[\Omega ight] = rac{\Delta v_D}{\Delta i_D}  imes 1000$
10	10.79	0.7332	1.5	0.7270	0062	-0,4846	12,74
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	Partner's Name	Set-Up (out of 10)	Data Collection (out of 10)	Participation (out of 5)
1	Brian Xu			
2	Lathika			

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